

<b>Notice of References Cited</b>	Application/Control No. 10/572,725		Applicant(s)/Patent Under Reexamination HAN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0119467 A1	06-2003	Welland et al.	455/260
*	B	US-2004/0048591 A1	03-2004	Kim et al.	455/168.1
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	D	US-			
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	F	US-			
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	K	US-			
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#### FOREIGN PATENT DOCUMENTS

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	N					
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#### NON-PATENT DOCUMENTS

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